

Search Notes

Application/Control No.

10/657,383

Examiner

Leigh C. Maier

Applicant(s)/Patent under
Reexamination

CHANG ET AL.

Art Unit

1623

SEARCHED

Class	Subclass	Date	Examiner
514	54, 53 61	2/3/2006	LCM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Reviewed prosecution history of parent 10/176,235 and inter partes reexam 95/000074	2/3/2006	LCM
-EAST and inventor search (transcript attached)	2/3/2006	LCM